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Titolo	Film literature index
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ISSN	0093-6758
Soggetti	Motion pictures Databases. Periodicals. Indexes. Electronic reference sources.
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Formato	Materiale a stampa
Livello bibliografico	Collezione
Sommario/riassunto	The Film Literature Index (FLI) annually indexes 150 film and television periodicals from 30 countries cover-to-cover and 200 other periodicals selectively for articles on film and television. The periodicals range from the scholarly to the popular. More than 2,000 subject headings provide detailed analysis of the articles. The FLI Online contains approximately 700,000 citations to articles, film reviews and book reviews published between 1976-2001. You can search the citations or browse by subject headings, browse by person names, browse by production titles, or browse by corporate names.

2. Record Nr.	UNINA9910953576703321
Autore	Sarid Dror
Titolo	Scanning force microscopy : with applications to electric, magnetic, and atomic forces // Dror Sarid
Pubbl/distr/stampa	New York ; , : Oxford University Press, , 2023
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Edizione	[Rev. ed.]
Descrizione fisica	1 online resource (xiii,263p. ) : ill
Collana	Oxford series in optical and imaging sciences ; ; 5 Oxford scholarship online
Disciplina	502.82
Soggetti	Scanning force microscopy Surfaces (Physics)
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Previous edition: 1991. Previously issued in print: 1994.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Intro -- Contents -- PREFACE TO THE REVISED EDITION -- PREFACE -- PART ONE. LEVERS AND NOISE -- Chapter 1 Mechanical Properties of Levers -- 1.1. Introduction -- 1.2. Stress and Strain -- 1.3. Moments -- 1.4. Spring Constant -- 1.5. The Rayleigh Solution to a Vibrating Lever -- 1.6. The Classical Solution to a Vibrating Lever -- 1.7. Normal Modes -- 1.8. Lumped Systems -- 1.9. Examples -- 1.10. Summary -- Chapter 2 Resonance Enhancement -- 2.1. Introduction -- 2.2. Bimorph Driver -- 2.3. Effective Spring Constant -- 2.4. Bimorph-Driven Lever -- 2.5. Sample-Driven Lever -- 2.6. Tip-Driven Lever -- 2.7. Summary -- Chapter 3 Sources of Noise -- 3.1. Introduction -- 3.2. General Discussion of Noise -- 3.3. Shot Noise -- 3.4. Resistor Johnson Noise -- 3.5. Laser Intensity Noise -- 3.6. Laser Phase Noise -- 3.7. Thermally Induced Lever Noise -- 3.8. Bimorph Noise -- 3.9. Lever Noise-Limited SNR -- 3.10. Experimental Characterization of Noise -- 3.11. Summary -- PART TWO. SCANNING FORCE

MICROSCOPES -- Chapter 4 Tunneling Detection System -- 4.1. Introduction -- 4.2. Theory -- 4.3. Perpendicular Arrangement -- 4.4. Cross Arrangement -- 4.5. Parallel Arrangement -- 4.6. Serial Arrangement -- 4.7. Single-Lever Arrangement -- 4.8. Summary -- Chapter 5 Capacitance Detection System -- 5.1. Introduction -- 5.2. Theory -- 5.3. Noise Considerations -- 5.4. Performance of Systems -- 5.5. Summary -- Chapter 6 Homodyne Detection System -- 6.1. Introduction -- 6.2. Theory -- 6.3. Noise Considerations -- 6.4. System Performance -- 6.5. Summary -- Chapter 7 Heterodyne Detection System -- 7.1. Introduction -- 7.2. Theory -- 7.3. Noise Considerations -- 7.4. Performance -- 7.5. Summary -- Chapter 8 Laser-Diode Feedback Detection System -- 8.1. Introduction -- 8.2. Theory -- 8.3. Noise Considerations -- 8.4. Performance -- 8.5. Summary.

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Sommario/riassunto

Includes information about the mapping of a variety of forces across surfaces, including basic theory, instrumentation, and applications. This book also includes research in SFM and a bibliography. It will be useful for academic and industrial researchers using SFM.

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